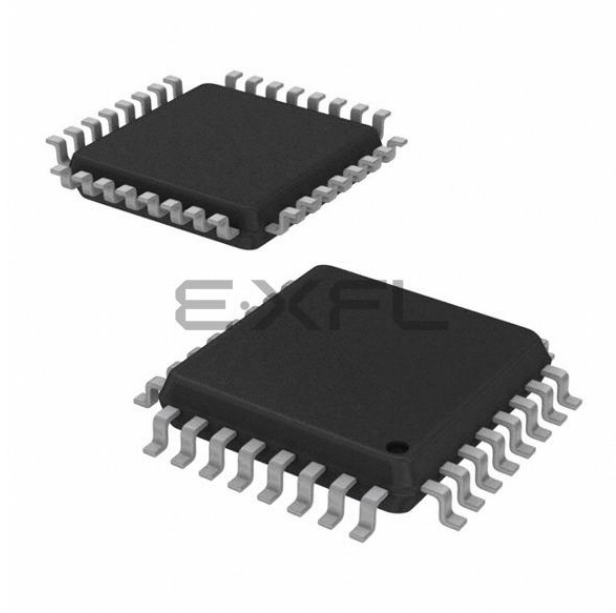

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8A
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	25
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	512 x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 7x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8af6246tasssy

1 Introduction

This datasheet refers to the STM8AF6246, STM8AF6248, STM8AF6266 and STM8AF6268 products with 16 to 32 Kbyte of Flash program memory.

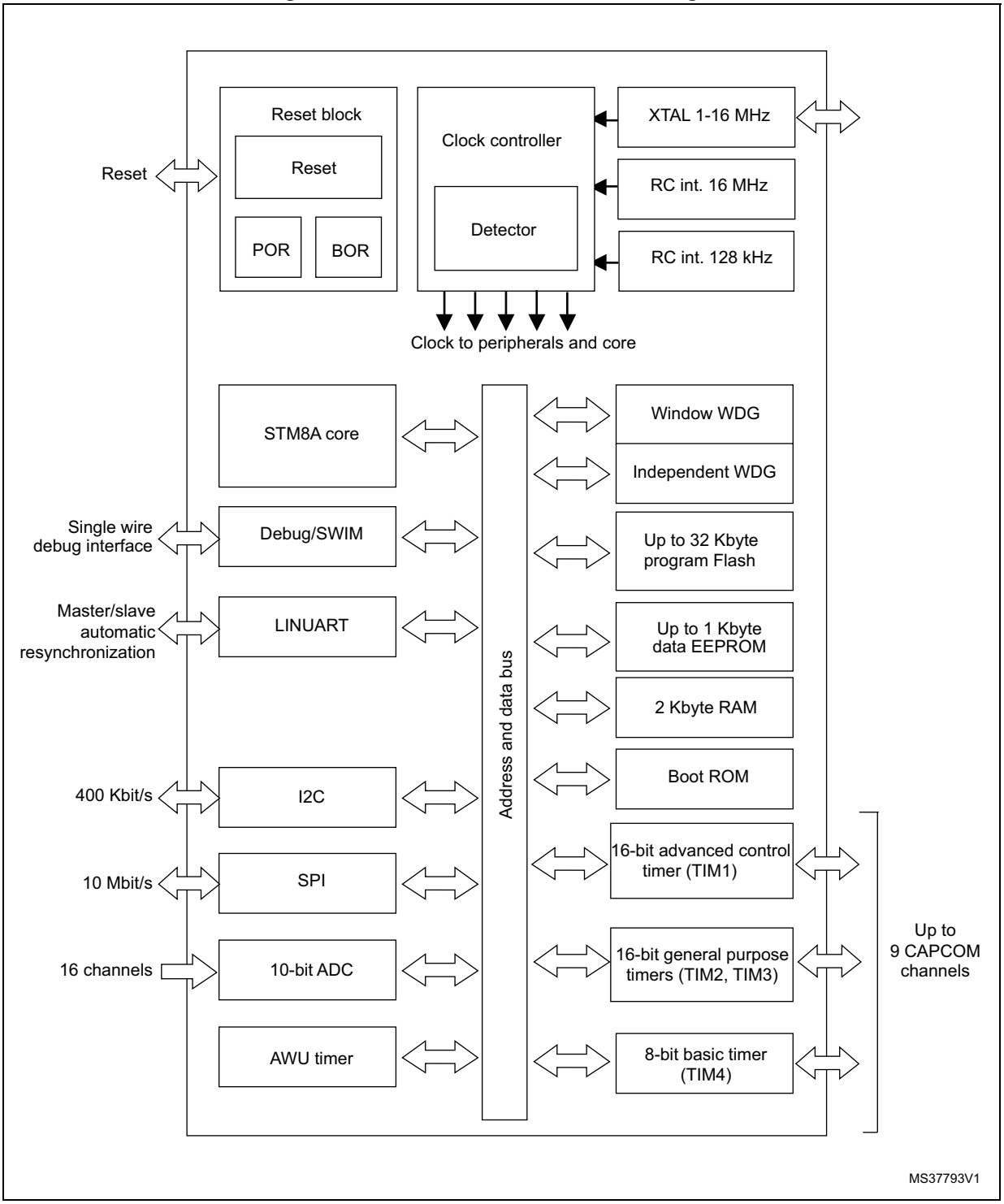
In the order code, the letter ‘F’ refers to product versions with data EEPROM and ‘H’ refers to product versions without data EEPROM. The identifiers ‘F’ and ‘H’ do not coexist in a given order code.

The datasheet contains the description of family features, pinout, electrical characteristics, mechanical data and ordering information.

- For complete information on the STM8A microcontroller memory, registers and peripherals, please refer to STM8S series and STM8AF series 8-bit microcontrollers reference manual (RM0016).
- For information on programming, erasing and protection of the internal Flash memory please refer to the STM8 Flash programming manual (PM0051).
- For information on the debug and SWIM (single wire interface module) refer to the STM8 SWIM communication protocol and debug module user manual (UM0470).
- For information on the STM8 core, please refer to the STM8 CPU programming manual (PM0044).

4 Block diagram

Figure 1. STM8AF6246/48/66/68 block diagram



1. Legend:
   ADC: Analog-to-digital converter
   beCAN: Controller area network
   BOR: Brownout reset
   I²C: Inter-integrated circuit multimaster interface
   IWDG: Independent window watchdog
   LINUART: Local interconnect network universal asynchronous receiver transmitter
   POR: Power on reset
   SPI: Serial peripheral interface
   SWIM: Single wire interface module
   USART: Universal synchronous asynchronous receiver transmitter
   Window WDG: Window watchdog

5.4.4 Read-out protection (ROP)

The STM8A provides a read-out protection of the code and data memory which can be activated by an option byte setting (see the ROP option byte in section 10).

The read-out protection prevents reading and writing Flash program memory, data memory and option bytes via the debug module and SWIM interface. This protection is active in all device operation modes. Any attempt to remove the protection by overwriting the ROP option byte triggers a global erase of the program and data memory.

The ROP circuit may provide a temporary access for debugging or failure analysis. The temporary read access is protected by a user defined, 8-byte keyword stored in the option bytes area. This keyword must be entered via the SWIM interface to temporarily unlock the device.

If desired, the temporary unlock mechanism can be permanently disabled by the user through OPT6/NOPT6 option bytes.

5.5 Clock controller

The clock controller distributes the system clock coming from different oscillators to the core and the peripherals. It also manages clock gating for low-power modes and ensures clock robustness.

5.5.1 Features

- **Clock sources**
  - 16 MHz high-speed internal RC oscillator (HSI)
  - 128 kHz low-speed internal RC (LSI)
  - 1-16 MHz high-speed external crystal (HSE)
  - Up to 16 MHz high-speed user-external clock (HSE user-ext)
- **Reset**: After reset the microcontroller restarts by default with an internal 2-MHz clock (16 MHz/8). The clock source and speed can be changed by the application program as soon as the code execution starts.
- **Safe clock switching**: Clock sources can be changed safely on the fly in Run mode through a configuration register. The clock signal is not switched until the new clock source is ready. The design guarantees glitch-free switching.
- **Clock management**: To reduce power consumption, the clock controller can stop the clock to the core or individual peripherals.
- **Wakeup**: In case the device wakes up from low-power modes, the internal RC oscillator (16 MHz/8) is used for quick startup. After a stabilization time, the device switches to the clock source that was selected before Halt mode was entered.
- **Clock security system (CSS)**: The CSS permits monitoring of external clock sources and automatic switching to the internal RC (16 MHz/8) in case of a clock failure.
- **Configurable main clock output (CCO)**: This feature permits to output a clock signal for use by the application.

Independent watchdog timer

The independent watchdog peripheral can be used to resolve malfunctions due to hardware or software failures.

It is clocked by the 128 kHz LSI internal RC clock source, and thus stays active even in case of a CPU clock failure. If the hardware watchdog feature is enabled through the device option bits, the watchdog is automatically enabled at power-on, and generates a reset unless the key register is written by software before the counter reaches the end of count.

5.7.2 Auto-wakeup counter

This counter is used to cyclically wakeup the device in Active-halt mode. It can be clocked by the internal 128 kHz internal low-frequency RC oscillator or external clock.

LSI clock can be internally connected to TIM3 input capture channel 1 for calibration.

5.7.3 Beeper

This function generates a rectangular signal in the range of 1, 2 or 4 kHz which can be output on a pin. This is useful when audible sounds without interference need to be generated for use in the application.

5.7.4 Advanced control and general purpose timers

STM8A devices described in this datasheet, contain up to three 16-bit advanced control and general purpose timers providing nine CAPCOM channels in total. A CAPCOM channel can be used either as input compare, output compare or PWM channel. These timers are named TIM1, TIM2 and TIM3.

Table 3. Advanced control and general purpose timers

Timer	Counter width	Counter type	Prescaler factor	Channels	Inverted outputs	Repetition counter	trigger unit	External trigger	Break input
TIM1	16-bit	Up/down	1 to 65536	4	3	Yes	Yes	Yes	Yes
TIM2	16-bit	Up	2^n n = 0 to 15	3	None	No	No	No	No
TIM3	16-bit	Up	2^n n = 0 to 15	2	None	No	No	No	No

Table 8. STM8AF6246/48/66/68 (32 Kbyte) microcontroller pin description(1)(2)

Pin number		Pin name	Type	Input			Output				Main function (after reset)	Default alternate function	Alternate function after remap [option bit]
LQFP48	VFQFPN/LQFP32			floating	wpu	Ext. interrupt	High sink	Speed	OD	PP			
1	1	NRST	I/O	-	**X**	-	-	-	-	-	Reset		-
2	2	PA1/OSCIN(3)	I/O	**X**	X	-	-	O1	X	X	**Port A1**	Resonator/crystal in	-
3	3	PA2/OSCOUT	I/O	**X**	X	X	-	O1	X	X	**Port A2**	Resonator/crystal out	-
4	-	V_{SSIO_1}	S	-	-	-	-	-	-	-	I/O ground		-
5	4	V_{SS}	S	-	-	-	-	-	-	-	Digital ground		-
6	5	VCAP	S	-	-	-	-	-	-	-	1.8 V regulator capacitor		-
7	6	V_{DD}	S	-	-	-	-	-	-	-	Digital power supply		-
8	7	V_{DDIO_1}	S	-	-	-	-	-	-	-	I/O power supply		-
-	8	PF4/AIN12(4)(5)	I/O	**X**	X		-	O1	X	X	**Port F4**	Analog input 12	-
9	-	PA3/TIM2_CH3	I/O	**X**	X	X	-	O1	X	X	**Port A3**	Timer 2 - channel 3	TIM3_CH1 [AFR1]
10	-	PA4	I/O	**X**	X	X	-	O3	X	X	**Port A4**		-
11	-	PA5	I/O	**X**	X	X	-	O3	X	X	**Port A5**		-
12	-	PA6	I/O	**X**	X	X	-	O3	X	X	**Port A6**		-
13	9	V_{DDA}	S	-	-	-	-	-	-	-	Analog power supply		-
14	10	V_{SSA}	S	-	-	-	-	-	-	-	Analog ground		-
15	-	PB7/AIN7	I/O	**X**	X	X	-	O1	X	X	**Port B7**	Analog input 7	-
16	-	PB6/AIN6	I/O	**X**	X	X	-	O1	X	X	**Port B6**	Analog input 6	-
17	11	PB5/AIN5	I/O	**X**	X	X	-	O1	X	X	**Port B5**	Analog input 5	I^2C_SDA [AFR6]
18	12	PB4/AIN4	I/O	**X**	X	X	-	O1	X	X	**Port B4**	Analog input 4	I^2C_SCL [AFR6]
19	13	PB3/AIN3	I/O	**X**	X	X	-	O1	X	X	**Port B3**	Analog input 3	TIM1_ETR [AFR5]
20	14	PB2/AIN2	I/O	**X**	X	X	-	O1	X	X	**Port B2**	Analog input	TIM1_NCC3 [AFR5]
21	15	PB1/AIN1	I/O	**X**	X	X	-	O1	X	X	**Port B1**	Analog input 1	TIM1_NCC2 [AFR5]
22	16	PB0/AIN0	I/O	**X**	X	X	-	O1	X	X	**Port B0**	Analog input 0	TIM1_NCC1 [AFR5]
23	-	PE7/AIN8	I/O	**X**	X		-	O1	X	X	**Port E7**	Analog input 8	-

Table 11. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 53E0	ADC	ADC _DB0RH	ADC data buffer register 0 high	0x00
0x00 53E1		ADC _DB0RL	ADC data buffer register 0 low	0x00
0x00 53E2		ADC _DB1RH	ADC data buffer register 1 high	0x00
0x00 53E3		ADC _DB1RL	ADC data buffer register 1 low	0x00
0x00 53E4		ADC _DB2RH	ADC data buffer register 2 high	0x00
0x00 53E5		ADC _DB2RL	ADC data buffer register 2 low	0x00
0x00 53E6		ADC _DB3RH	ADC data buffer register 3 high	0x00
0x00 53E7		ADC _DB3RL	ADC data buffer register 3 low	0x00
0x00 53E8		ADC _DB4RH	ADC data buffer register 4 high	0x00
0x00 53E9		ADC _DB4RL	ADC data buffer register 4 low	0x00
0x00 53EA		ADC _DB5RH	ADC data buffer register 5 high	0x00
0x00 53EB		ADC _DB5RL	ADC data buffer register 5 low	0x00
0x00 53EC		ADC _DB6RH	ADC data buffer register 6 high	0x00
0x00 53ED		ADC _DB6RL	ADC data buffer register 6 low	0x00
0x00 53EE		ADC _DB7RH	ADC data buffer register 7 high	0x00
0x00 53EF		ADC _DB7RL	ADC data buffer register 7 low	0x00
0x00 53F0		ADC _DB8RH	ADC data buffer register 8 high	0x00
0x00 53F1		ADC _DB8RL	ADC data buffer register 8 low	0x00
0x00 53F2		ADC _DB9RH	ADC data buffer register 9 high	0x00
0x00 53F3		ADC _DB9RL	ADC data buffer register 9 low	0x00
0x00 53F4 to 0x00 53FF	Reserved area (12 bytes)			
0x00 5400	ADC	ADC _CSR	ADC control/status register	0x00
0x00 5401		ADC_CR1	ADC configuration register 1	0x00
0x00 5402		ADC_CR2	ADC configuration register 2	0x00
0x00 5403		ADC_CR3	ADC configuration register 3	0x00
0x00 5404		ADC_DRH	ADC data register high	0xXX
0x00 5405		ADC_DRL	ADC data register low	0xXX
0x00 5406		ADC_TDRH	ADC Schmitt trigger disable register high	0x00
0x00 5407		ADC_TDRL	ADC Schmitt trigger disable register low	0x00
0x00 5408		ADC _HTRH	ADC high threshold register high	0xFF
0x00 5409		ADC_HTRL	ADC high threshold register low	0x03
0x00 540A		ADC _LTRH	ADC low threshold register high	0x00

8 Interrupt table

Table 14. STM8A interrupt table

Priority	Source block	Description	Interrupt vector address	Wakeup from Halt	Comments
-	Reset	Reset	0x00 8000	Yes	User RESET vector
-	TRAP	SW interrupt	0x00 8004	-	-
0	TLI	External top level interrupt	0x00 8008	-	-
1	AWU	Auto-wakeup from Halt	0x00 800C	Yes	-
2	Clock controller	Main clock controller	0x00 8010	-	-
3	MISC	Ext interrupt E0	0x00 8014	Yes	Port A interrupts
4	MISC	Ext interrupt E1	0x00 8018	Yes	Port B interrupts
5	MISC	Ext interrupt E2	0x00 801C	Yes	Port C interrupts
6	MISC	Ext interrupt E3	0x00 8020	Yes	Port D interrupts
7	MISC	Ext interrupt E4	0x00 8024	Yes	Port E interrupts
8	Reserved(1)	-	-	-	-
9	Reserved(1)	-	-	-	-
10	SPI	End of transfer	0x00 8030	Yes	-
11	Timer 1	Update/overflow/ trigger/break	0x00 8034	-	-
12	Timer 1	Capture/compare	0x00 8038	-	-
13	Timer 2	Update/overflow	0x00 803C	-	-
14	Timer 2	Capture/compare	0x00 8040	-	-
15	Timer 3	Update/overflow	0x00 8044	-	-
16	Timer 3	Capture/compare	0x00 8048	-	-
17	Reserved(1)	-	-	-	-
18	Reserved(1)	-	-	-	-
19	I^2C	I^2C interrupts	0x00 8054	Yes	-
20	LINUART	Tx complete/error	0x00 8058	-	-
21	LINUART	Receive data full reg.	0x00 805C	-	-
22	ADC	End of conversion	0x00 8060	-	-
23	Timer 4	Update/overflow	0x00 8064	-	-
24	EEPROM	End of Programming/ Write in not allowed area	0x00 8068	-	-

1. All reserved and unused interrupts must be initialized with ‘IRET’ for robust programming.

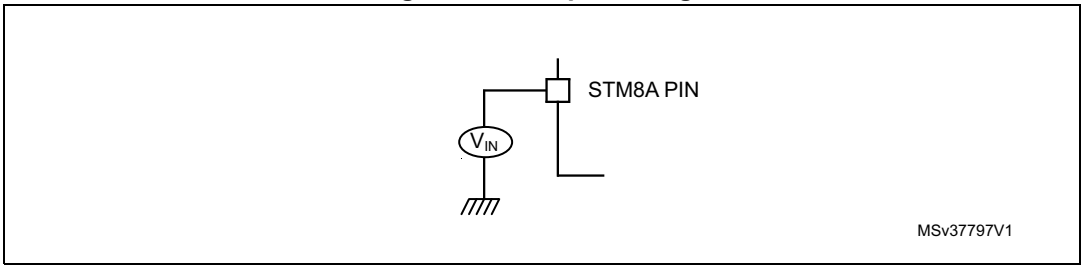
Table 16. Option byte description

Option byte no.	Description
OPT0	**ROP[7:0]: Memory readout protection (ROP)** 0xAA: Enable readout protection (write access via SWIM protocol) *Note: Refer to STM8S series and STM8AF series 8-bit microcontrollers reference manual (RM0016) section on Flash/EEPROM memory readout protection for details.*
OPT1	**UBC[5:0]: User boot code area** 0x00: No UBC, no write-protection 0x01: Page 0 to 1 defined as UBC, memory write-protected 0x02: Page 0 to 3 defined as UBC, memory write-protected 0x03 to 0x3F: Pages 4 to 63 defined as UBC, memory write-protected *Note: Refer to STM8S series and STM8AF series 8-bit microcontrollers reference manual (RM0016) section on Flash/EEPROM write protection for more details.*
OPT2	**AFR7: Alternate function remapping option 7** 0: Port D4 alternate function = TIM2_CH1 1: Port D4 alternate function = BEEP **AFR6: Alternate function remapping option 6** 0: Port B5 alternate function = AIN5, port B4 alternate function = AIN4 1: Port B5 alternate function = I^2C_SDA, port B4 alternate function = I^2C_SCL. **AFR5: Alternate function remapping option 5** 0: Port B3 alternate function = AIN3, port B2 alternate function = AIN2, port B1 alternate function = AIN1, port B0 alternate function = AIN0. 1: Port B3 alternate function = TIM1_ETR, port B2 alternate function = TIM1_CH3N, port B1 alternate function = TIM1_CH2N, port B0 alternate function = TIM1_CH1N. **AFR4: Alternate function remapping option 4** Reserved, bit must be kept at “0” **AFR3: Alternate function remapping option 3** 0: Port D0 alternate function = TIM3_CH2 1: Port D0 alternate function = TIM1_BKIN **AFR2: Alternate function remapping option 2** 0: Port D0 alternate function = TIM3_CH2 1: Port D0 alternate function = CLK_CCO *Note: AFR2 option has priority over AFR3 if both are activated* **AFR1: Alternate function remapping option 1** 0: Port A3 alternate function = TIM2_CH3, port D2 alternate function TIM3_CH1. 1: Port A3 alternate function = TIM3_CH1, port D2 alternate function TIM2_CH3. **AFR0: Alternate function remapping option 0** 0: Port D3 alternate function = TIM2_CH2 1: Port D3 alternate function = ADC_ETR

10.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in *Figure 7*.

Figure 7. Pin input voltage



10.2 Absolute maximum ratings

Stresses above those listed as 'absolute maximum ratings' may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 17. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
V_{DDx} - V_{SS}	Supply voltage (including V_{DDA} and V_{DDIO})(1)	-0.3	6.5	V
V_{IN}	Input voltage on true open drain pins (PE1, PE2)(2)	V_{SS} - 0.3	6.5	V
	Input voltage on any other pin(2)	V_{SS} - 0.3	V_{DD} + 0.3	
$\lvert V_{DDx} - V_{DD} \rvert$	Variations between different power pins	-	50	mV
$\lvert V_{SSx} - V_{SS} \rvert$	Variations between all the different ground pins	-	50	
V_{ESD}	Electrostatic discharge voltage	see *Absolute maximum ratings (electrical sensitivity) on page 76*		

1. All power (V_{DD}, V_{DDIO}, V_{DDA}) and ground (V_{SS}, V_{SSIO}, V_{SSA}) pins must always be connected to the external power supply
2. $I_{INJ(PIN)}$ must never be exceeded. This is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{INJ(PIN)}$ value. A positive injection is induced by $V_{IN} > V_{DD}$ while a negative injection is induced by $V_{IN} < V_{SS}$. For true open-drain pads, there is no positive injection current, and the corresponding V_{IN} maximum must always be respected

Table 22. Operating conditions at power-up/power-down

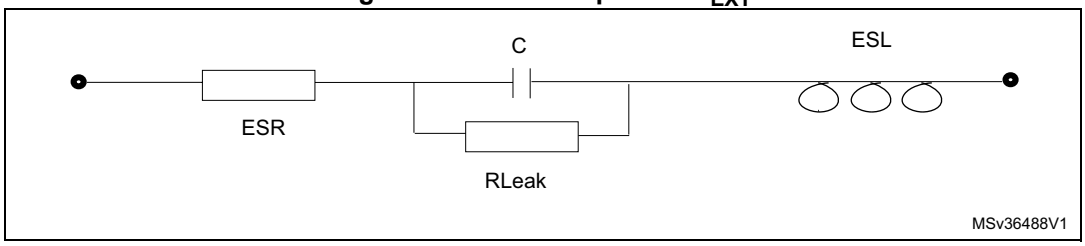
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
t_{VDD}	V_{DD} rise time rate	-	2(1)	-	∞	µs/V
	V_{DD} fall time rate	-	2(1)	-	∞	
t_{TEMP}	Reset release delay	V_{DD} rising	-	1	1.7	ms
	Reset generation delay	V_{DD} falling	-	3	-	µs
V_{IT+}	Power-on reset threshold(2) (3)	-	2.65	2.8	2.95	V
V_{IT-}	Brown-out reset threshold	-	2.58	2.73	2.88	
$V_{HYS(BOR)}$	Brown-out reset hysteresis	-	-	70(1)	-	mV

1. Guaranteed by design, not tested in production
2. If V_{DD} is below 3 V, the code execution is guaranteed above the V_{IT-} and V_{IT+} thresholds. RAM content is kept. The EEPROM programming sequence must not be initiated.
3. There is inrush current into V_{DD} present after device power on to charge C_{EXT} capacitor. This inrush energy depends from C_{EXT} capacitor value. For example, a C_{EXT} of 1µF requires Q=1 µF x 1.8V = 1.8 µC.

10.3.1 VCAP external capacitor

Stabilization for the main regulator is achieved connecting an external capacitor C_{EXT} to the V_{CAP} pin. C_{EXT} is specified in *Table 21*. Care should be taken to limit the series inductance to less than 15 nH.

Figure 9. External capacitor C_{EXT}



1. Legend: ESR is the equivalent series resistance and ESL is the equivalent inductance.

10.3.2 Supply current characteristics

The current consumption is measured as described in *Figure 6 on page 49* and *Figure 7 on page 50*.

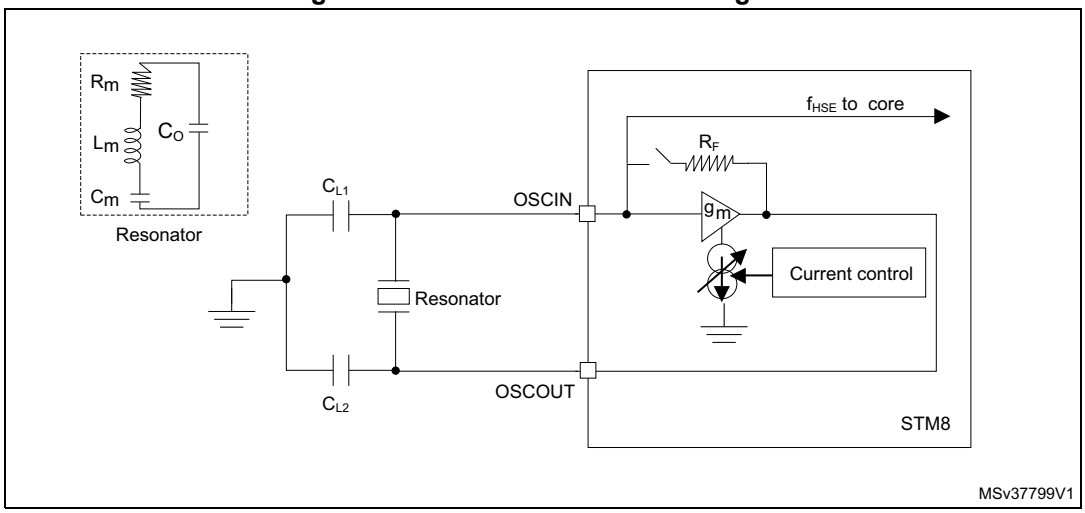
If not explicitly stated, general conditions of temperature and voltage apply.

Table 23. Total current consumption in Run, Wait and Slow mode. General conditions for V_{DD} apply, T_A = -40 to 150 °C

Symbol	Parameter	Conditions		Typ	Max	Unit
$I_{DD(RUN)}$(1)	Supply current in Run mode	All peripherals clocked, code executed from Flash program memory, HSE external clock (without resonator)	f_{CPU} = 16 MHz	7.4	14	mA
			f_{CPU} = 8 MHz	4.0	7.4(2)	
			f_{CPU} = 4 MHz	2.4	4.1(2)	
			f_{CPU} = 2 MHz	1.5	2.5	
$I_{DD(RUN)}$(1)	Supply current in Run mode	All peripherals clocked, code executed from RAM and EEPROM, HSE external clock (without resonator)	f_{CPU} = 16 MHz	3.7	5.0	
			f_{CPU} = 8 MHz	2.2	3.0(2)	
			f_{CPU} = 4 MHz	1.4	2.0(2)	
			f_{CPU} = 2 MHz	1.0	1.5	
$I_{DD(WFI)}$(1)	Supply current in Wait mode	CPU stopped, all peripherals off, HSE external clock	f_{CPU} = 16 MHz	1.65	2.5	
			f_{CPU} = 8 MHz	1.15	1.9(2)	
			f_{CPU} = 4 MHz	0.90	1.6(2)	
			f_{CPU} = 2 MHz	0.80	1.5	
$I_{DD(SLOW)}$(1)	Supply current in Slow mode	f_{CPU} scaled down, all peripherals off, code executed from RAM	Ext. clock 16 MHz f_{CPU} = 125 kHz	1.50	1.95	
			LSI internal RC f_{CPU} = 128 kHz	1.50	1.80(2)	

1. The current due to I/O utilization is not taken into account in these values.
2. Values not tested in production. Design guidelines only.

Figure 17. HSE oscillator circuit diagram



HSE oscillator critical g_m formula

The crystal characteristics have to be checked with the following formula:

$$g_m \gg g_{mcrit}$$

where g_{mcrit} can be calculated with the crystal parameters as follows:

$$g_{mcrit} = (2 \times \Pi \times {}^{f}HSE)^2 \times R_m(2Co + C)^2$$

R_m: Notional resistance (see crystal specification)
L_m: Notional inductance (see crystal specification)
C_m: Notional capacitance (see crystal specification)
Co: Shunt capacitance (see crystal specification)
$C_{L1} = C_{L2} = C$: Grounded external capacitance

10.3.4 Internal clock sources and timing characteristics

Subject to general operating conditions for V_{DD} and T_A.

High speed internal RC oscillator (HSI)

Table 30. HSI oscillator characteristics

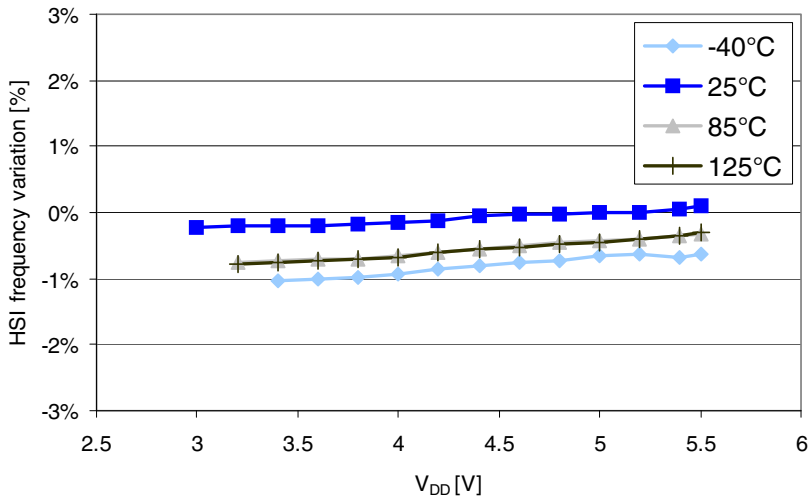
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI}	Frequency	-	-	16	-	MHz

Table 30. HSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
ACC_{HS}	HSI oscillator user trimming accuracy	Trimmed by the application for any V_{DD} and T_A conditions	-1(1)	-	1(1)	%
			-0.5(1)	-	0.5(1)	
	HSI oscillator accuracy (factory calibrated)	3.0 V ≤ V_{DD} ≤ 5.5 V, -40 °C ≤ T_A ≤ 150 °C	-5	-	5	
		3.0V ≤ V_{DD} ≤ 5.5V, -40°C ≤ T_A ≤ 125 °C	-2.5(2)	-	2.5(2)	
$t_{su(HSI)}$	HSI oscillator wakeup time	-	-	-	2(3)	µs

1. Depending on option byte setting (OPT3 and NOPT3)
2. These values are guaranteed for STM8AF62x6ITx order codes only.
3. Guaranteed by characterization, not tested in production

Figure 18. Typical HSI frequency vs V_{DD}



Low speed internal RC oscillator (LSI)

Subject to general operating conditions for V_{DD} and T_A.

Table 31. LSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSI}	Frequency	-	112	128	144	kHz
$t_{su(LSI)}$	LSI oscillator wakeup time	-	-	-	7(1)	µs

1. Data based on characterization results, not tested in production.

Figure 27. Typ. V_{OL} @ V_{DD} = 3.3 V (high sink ports)

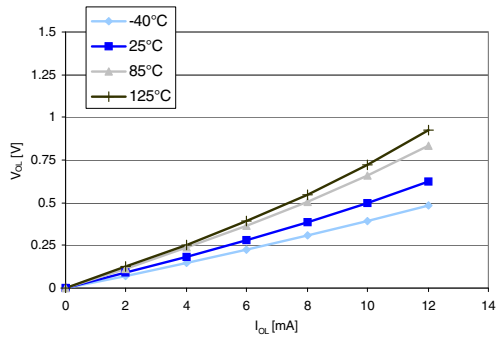


Figure 28. Typ. V_{OL} @ V_{DD} = 5.0 V (high sink ports)

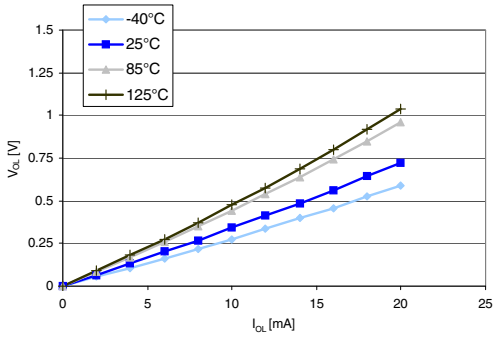


Figure 29. Typ. V_{DD} - V_{OH} @ V_{DD} = 3.3 V (standard ports)

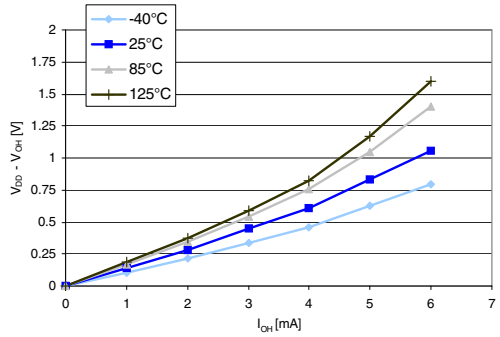


Figure 30. Typ. V_{DD} - V_{OH} @ V_{DD} = 5.0 V (standard ports)

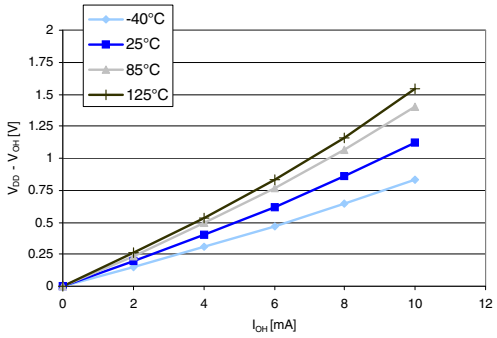


Figure 31. Typ. V_{DD} - V_{OH} @ V_{DD} = 3.3 V (high sink ports)

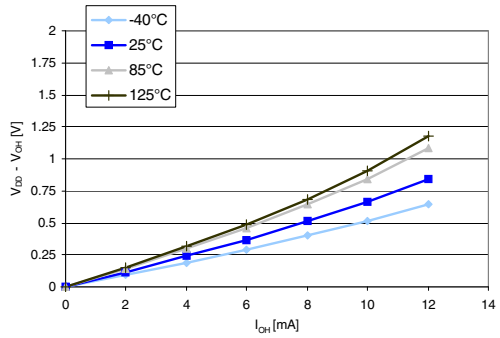
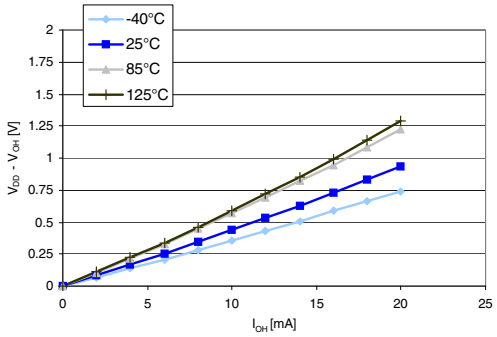


Figure 32. Typ. V_{DD} - V_{OH} @ V_{DD} = 5.0 V (high sink ports)



10.3.10 I²C interface characteristics

Table 39. I²C characteristics

Symbol	Parameter	Standard mode I²C		Fast mode I²C(1)		Unit
		Min(2)	Max(2)	Min(2)	Max(2)	
$t_{w(SCLL)}$	SCL clock low time	4.7	-	1.3	-	µs
$t_{w(SCLH)}$	SCL clock high time	4.0	-	0.6	-	
$t_{su(SDA)}$	SDA setup time	250	-	100	-	ns
$t_{h(SDA)}$	SDA data hold time	0(3)	-	0(4)	900(3)	
$t_{r(SDA)}$ $t_{r(SCL)}$	SDA and SCL rise time (V_{DD} = 3 to 5.5 V)	-	1000	-	300	
$t_{f(SDA)}$ $t_{f(SCL)}$	SDA and SCL fall time (V_{DD} = 3 to 5.5 V)	-	300	-	300	
$t_{h(STA)}$	START condition hold time	4.0	-	0.6	-	µs
$t_{su(STA)}$	Repeated START condition setup time	4.7	-	0.6	-	
$t_{su(STO)}$	STOP condition setup time	4.0	-	0.6	-	
$t_{w(STO:STA)}$	STOP to START condition time (bus free)	4.7	-	1.3	-	
C_b	Capacitive load for each bus line	-	400	-	400	pF

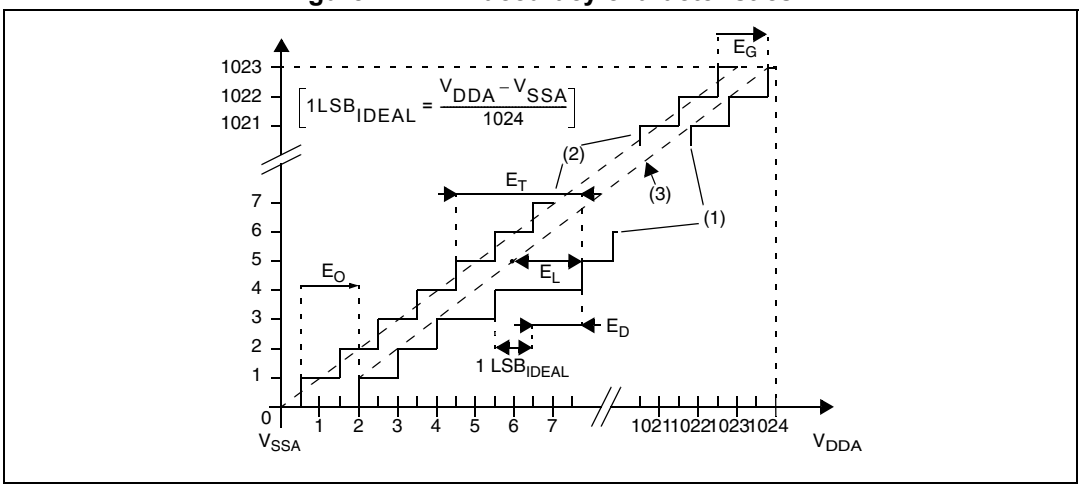
1. f_{MASTER}, must be at least 8 MHz to achieve max fast I²C speed (400 kHz)
2. Data based on standard I²C protocol requirement, not tested in production
3. The maximum hold time of the start condition has only to be met if the interface does not stretch the low time
4. The device must internally provide a hold time of at least 300 ns for the SDA signal in order to bridge the undefined region of the falling edge of SCL

Table 41. ADC accuracy for V_{DDA} = 5 V

Symbol	Parameter	Conditions	Typ	Max(1)	Unit
$\|E_T\|$	Total unadjusted error(2)	f_{ADC} = 2 MHz	1.4	3(3)	LSB
$\|E_O\|$	Offset error(2)		0.8	3	
$\|E_G\|$	Gain error(2)		0.1	2	
$\|E_D\|$	Differential linearity error(2)		0.9	1	
$\|E_L\|$	Integral linearity error(2)		0.7	1.5	
$\|E_T\|$	Total unadjusted error(2)	f_{ADC} = 4 MHz	1.9(4)	4(4)	
$\|E_O\|$	Offset error(2)		1.3(4)	4(4)	
$\|E_G\|$	Gain error(2)		0.6(4)	3(4)	
$\|E_D\|$	Differential linearity error(2)		1.5(4)	2(4)	
$\|E_L\|$	Integral linearity error(2)		1.2(4)	1.5(4)	

1. Max value is based on characterization, not tested in production.
2. ADC accuracy vs. injection current: Any positive or negative injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 10.3.6* does not affect the ADC accuracy.
3. TUE 2LSB can be reached on specific sales types on the whole temperature range.
4. Target values.

Figure 41. ADC accuracy characteristics



1. Example of an actual transfer curve
2. The ideal transfer curve
3. End point correlation line
   E_T = Total unadjusted error: Maximum deviation between the actual and the ideal transfer curves.
   E_O = Offset error: Deviation between the first actual transition and the first ideal one.
   E_G = Gain error: Deviation between the last ideal transition and the last actual one.
   E_D = Differential linearity error: Maximum deviation between actual steps and the ideal one.
   E_L = Integral linearity error: Maximum deviation between any actual transition and the end point correlation line.

10.3.12 EMC characteristics

Susceptibility tests are performed on a sample basis during product characterization.

Functional EMS (electromagnetic susceptibility)

While executing a simple application (toggling 2 LEDs through I/O ports), the product is stressed by two electromagnetic events until a failure occurs (indicated by the LEDs).

- **ESD**: Electrostatic discharge (positive and negative) is applied on all pins of the device until a functional disturbance occurs. This test conforms with the IEC 1000-4-2 standard.
- **FTB**: A burst of fast transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test conforms with the IEC 1000-4-4 standard.

A device reset allows normal operations to be resumed. The test results are given in the table below based on the EMS levels and classes defined in application note AN1709.

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical data corruption (control registers...)

Prequalification trials

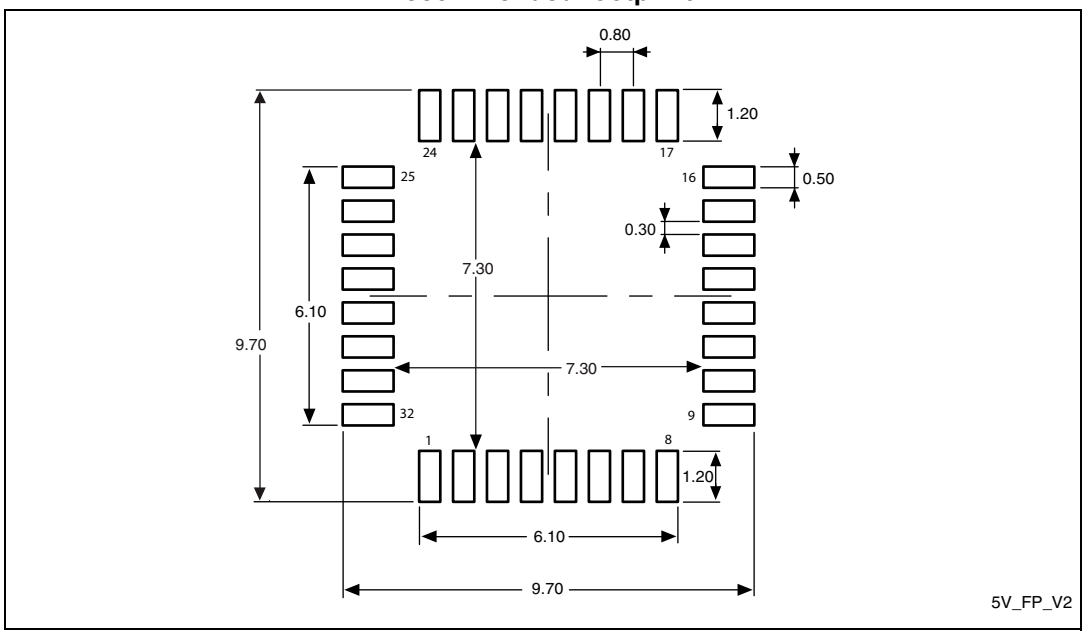
Most of the common failures (unexpected reset and program counter corruption) can be recovered by applying a low state on the NRST pin or the oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Table 42. EMS data

Symbol	Parameter	Conditions	Level/class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, T_A= 25 °C, f_{MASTER} = 16 MHz (HSI clock), Conforms to IEC 1000-4-2	3/B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD}= 3.3 V, T_A= 25 °C, f_{MASTER} = 16 MHz (HSI clock), Conforms to IEC 1000-4-4	4/A

Figure 49. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package recommended footprint

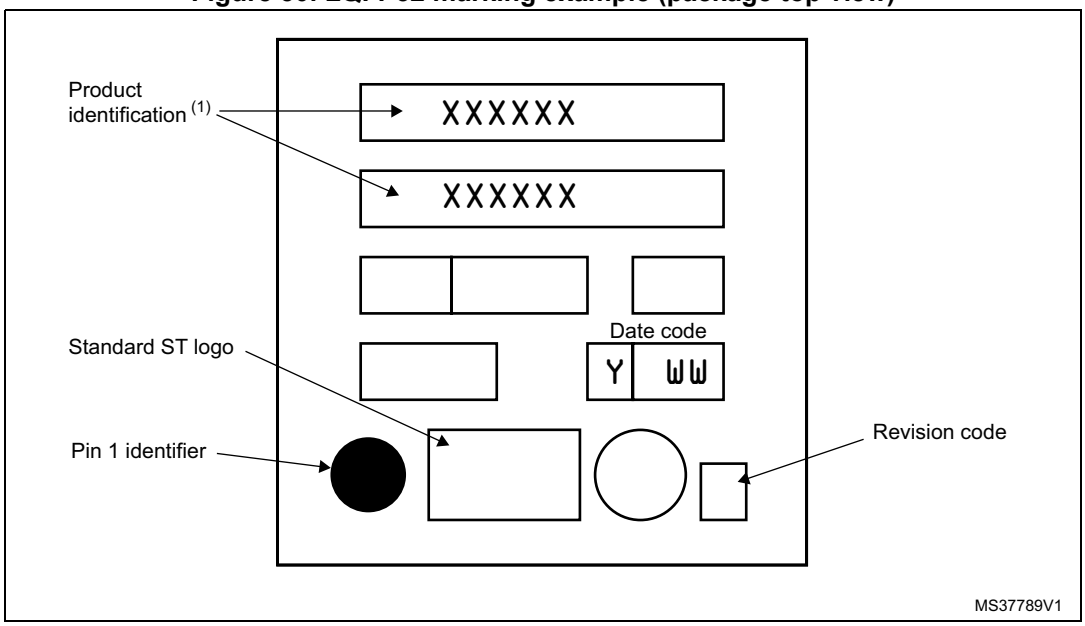


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 50. LQFP32 marking example (package top view)



13.3 Programming tools

During the development cycle, STice provides in-circuit programming of the STM8A Flash microcontroller on the user application board via the SWIM protocol. Additional tools are used to include a low-cost in-circuit programmer as well as ST socket boards, which provide dedicated programming platforms with sockets for programming the user STM8A.

For production environments, programmers will include a complete range of gang and automated programming solutions from third-party tool developers already supplying programmers for the STM8 family.